

IN THE CLAIMS:

This listing of claims will replace all prior versions, and listings of claims in the application:

1. (Currently Amended) A device for analyzing a plurality of sample components, comprising:

a drawn substrate having a length, ~~the drawn substrate having~~ and at least two drawn channels formed therein, said drawn substrate and at least two drawn channels being drawn from a preform having corresponding channels formed therein;

the drawn channels extending in a direction parallel to the length, and the substrate including inlets and outlets in cooperating relation with the drawn channels .

2. (Withdrawn) A method of analyzing by introducing a plurality of sample components to a drawn substrate having a length, the drawn substrate having at least two drawn channels formed therein;

the drawn channels extending in a direction parallel to the length, and the substrate includes inlets and outlets disposed in cooperating relation with the drawn channels.

3. (Previously Amended) A device as in claim 1, further comprising at least one endcap substrate having at least one endcap channel, the at least one endcap channel being in fluid communication with at least one channel selected from the group comprising: a selected one of the drawn channels, a plurality of the drawn channels, another endcap channel and combinations thereof.

4. (Previously Amended) A device as in claim 1 or 3 with at least one drawn channel having a cross sectional area in the range of 0.0001mm^2 to 1mm^2 .

5. (Previously Amended) A device as in claim 1 or 3 with at least one drawn channel having a length in the range of 1mm to 1km.

6. (Withdrawn) A device as in claim 1 or 3, wherein the drawn substrate is utilized in a micro electro mechanical system.

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